

# Gaia-based GFA metrology tweaks

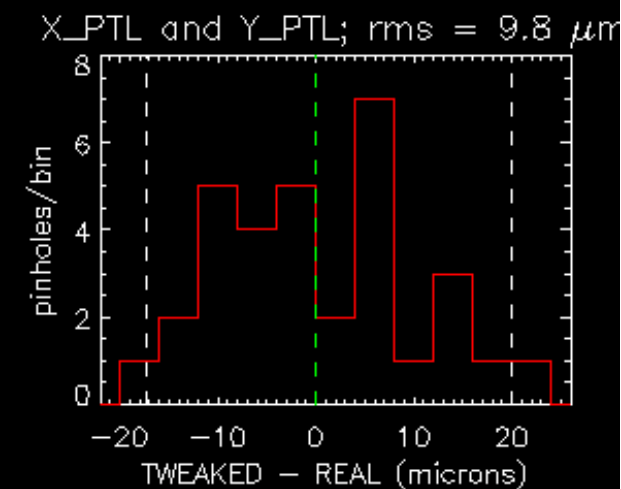
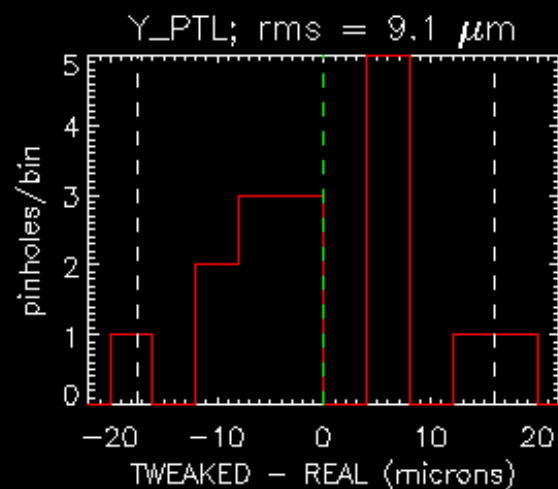
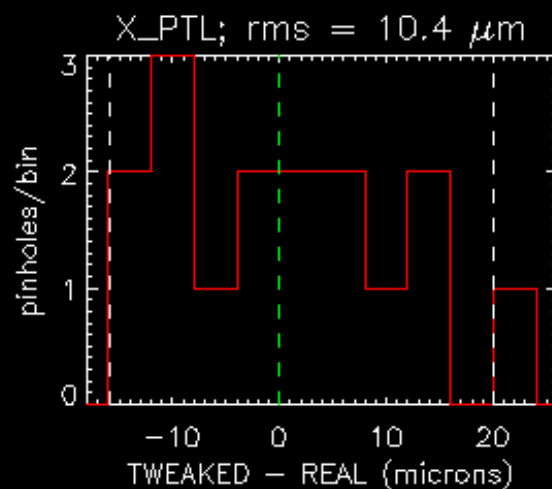
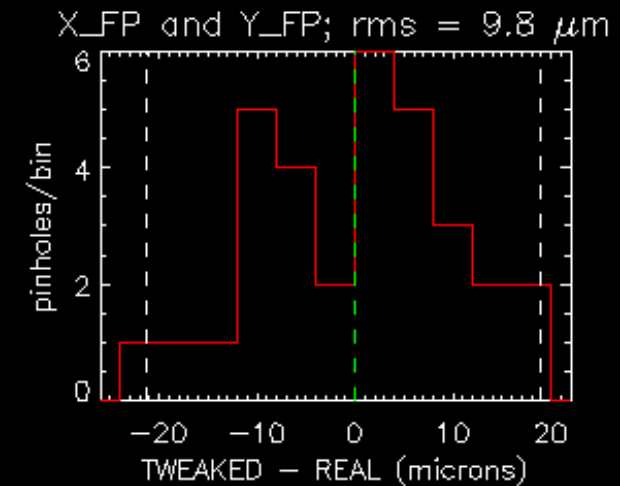
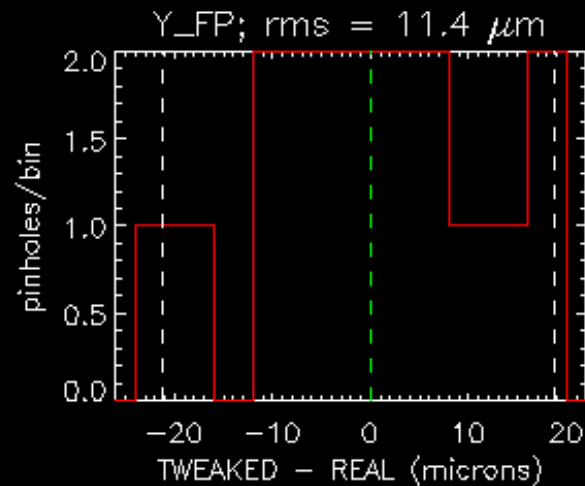
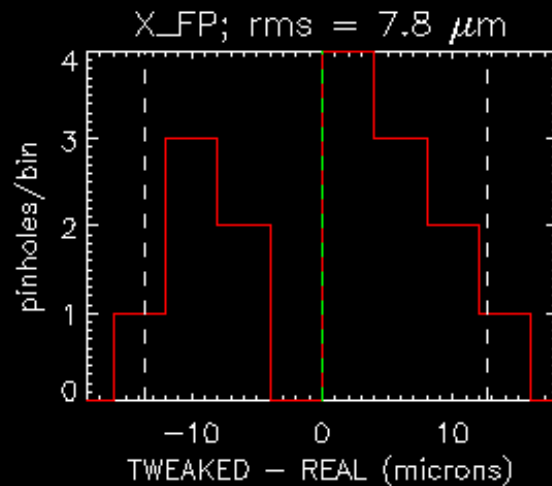
# Approach

- In addition to providing pseudo metrology for the two guide cameras lacking real metrology in fp-metrology.csv, the planar surfaces  $x_{fp}(x_{gfa}, y_{gfa})$  and  $y_{fp}(x_{gfa}, y_{gfa})$  can also provide tweaked metrology for the guide cameras with real metrology in fp-metrology.csv
- The idea is that the focal plane corner coordinates provided by the planar surface models should encapsulate information about the Gaia star position residuals relative to the real metrology provided in fp-metrology.csv for GUIDE0, GUIDE2, GUIDE5 and GUIDE8 even though the analysis isn't framed explicitly in terms of metrology residuals

# Approach

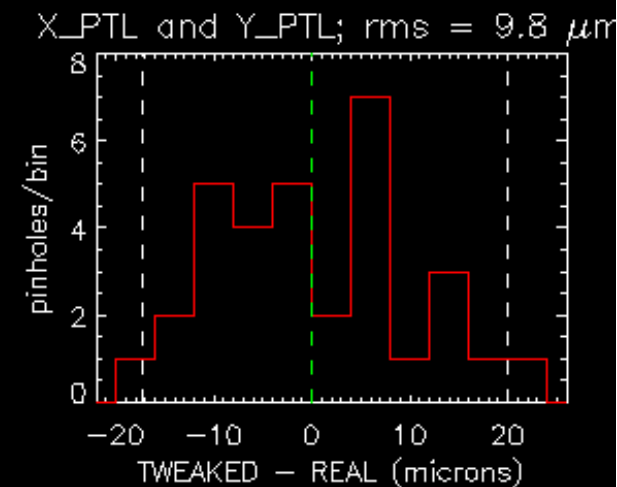
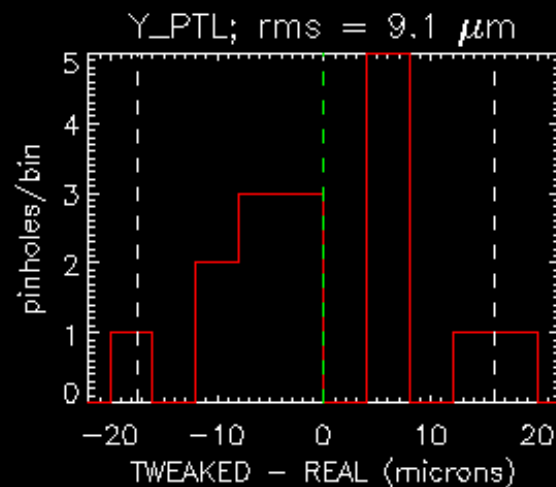
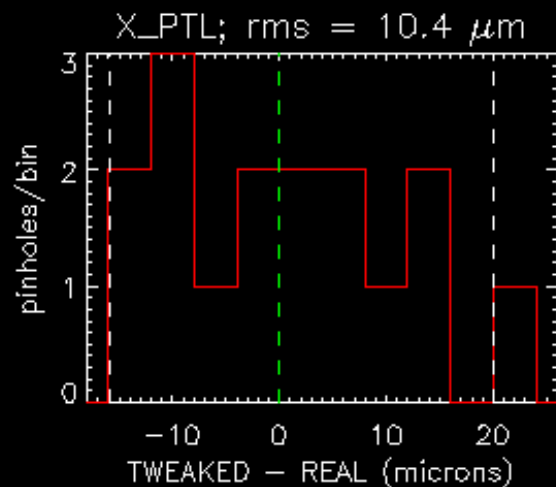
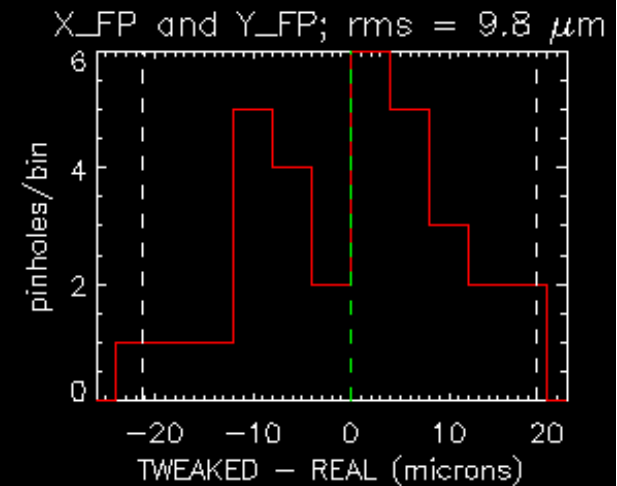
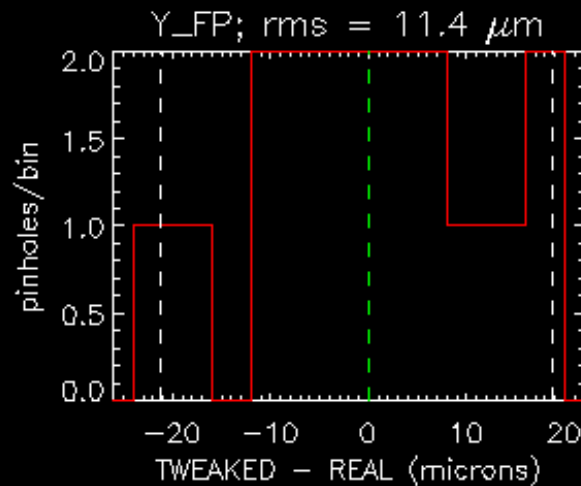
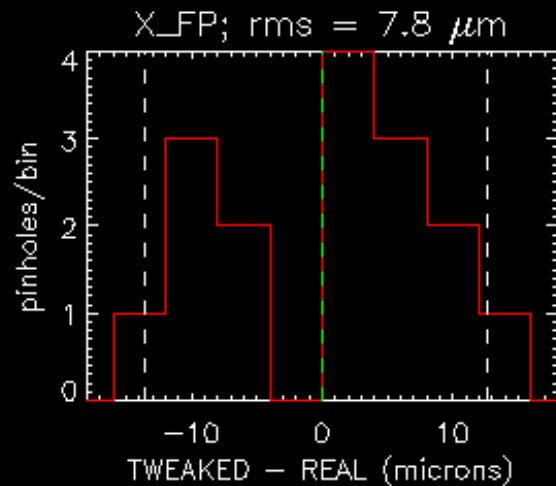
- The same script I wrote to generate GUIDE3 and GUIDE7 pseudo metrology can also output the pseudo metrology corner coordinates for cameras with real metrology in fp-metrology.csv
  - [https://github.com/desihub/desimeter/blob/master/bin/write\\_guide3\\_guide7\\_patch](https://github.com/desihub/desimeter/blob/master/bin/write_guide3_guide7_patch)
- There are only two minor differences in methodology for the cameras with real metrology relative to those without real metrology in fp-metrology.csv
  - For the z\_ptl and z\_fp coordinates of cameras with real metrology, I adopt their real metrology values rather than the average of these quantities across cameras with real metrology
  - When figuring out the shifts to transform between focal surface and physical CCD coordinates, I begin by guessing the XYZ pinhole coordinates based on the real metrology already available for the specific camera in question, rather than starting with a guess that averages across cameras with real metrology

# Results



- These plots only include GUIDE0, GUIDE2, GUIDE5, GUIDE8 (the guide cameras with real metrology in fp-metrology.csv)
- RMS values are computed relative to zero
- White vertical dashed lines are the min and max values within each panel

# Results

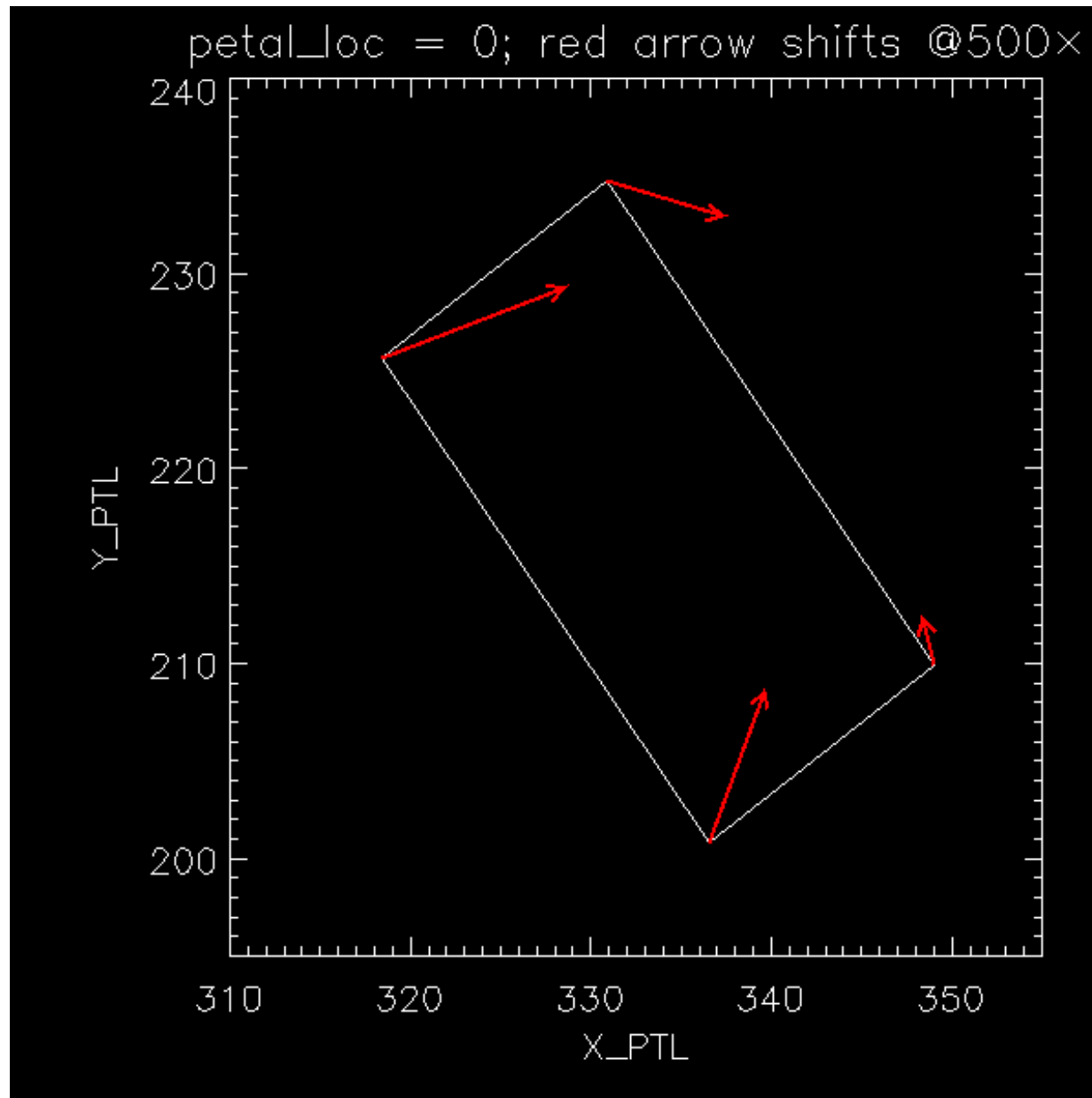


- The largest shift for any pinhole in any of X\_PTL, Y\_PTL, X\_FP, Y\_FP is 21.2 microns
- 21.2 microns also happens to be the largest 2D shift inferred for any of the 16 pinholes from GUIDE0, GUIDE2, GUIDE5, GUIDE8

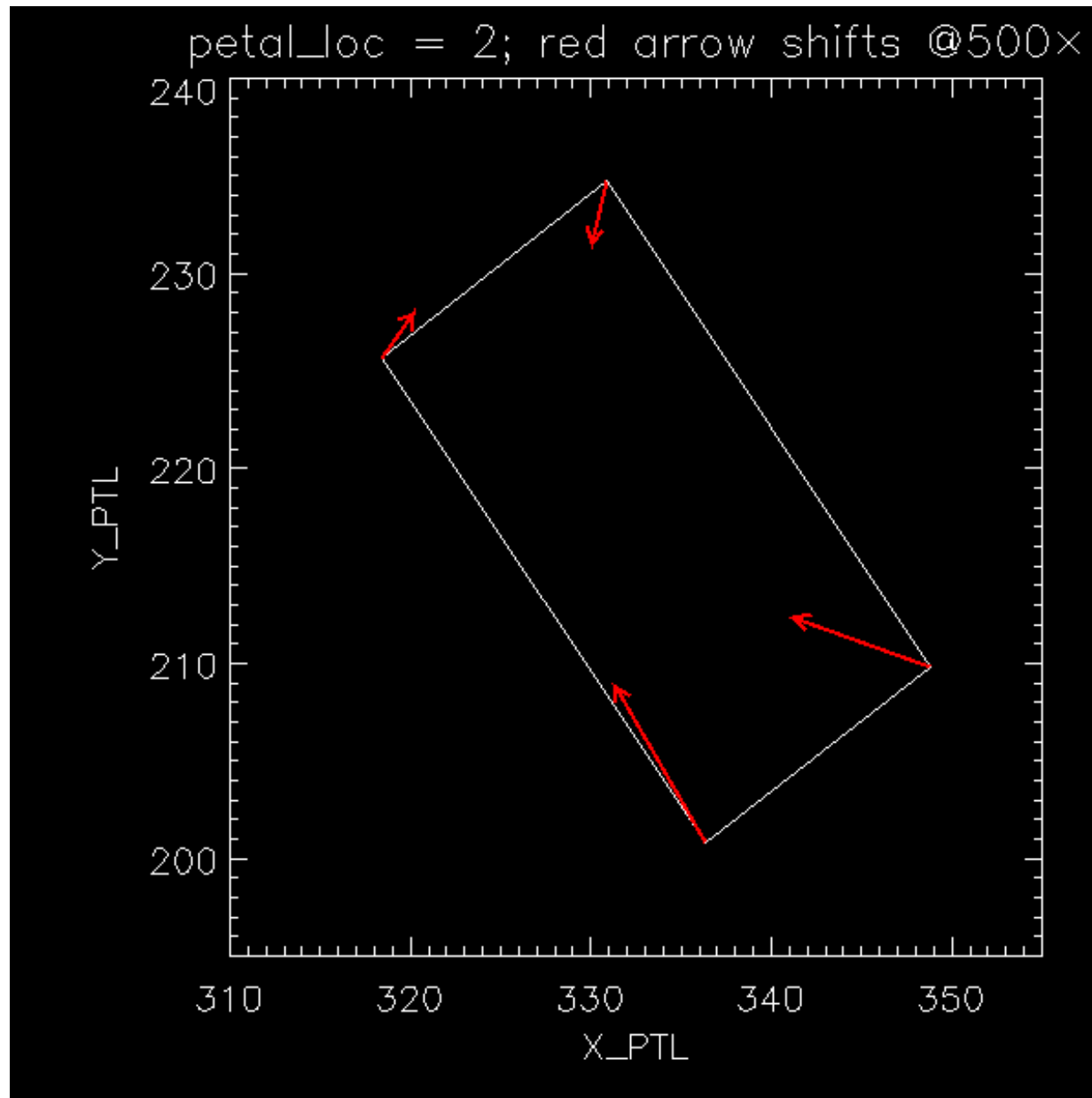
# Sanity check: running another iteration

- I ran another iteration of my entire analysis (i.e., re-fitting all FieldModel's and planar surfaces) where I replaced all guide GFA metrology with my pseudo metrology, to check for indications of non-convergence
- The largest per coordinate shift in the second iteration of the pseudo metrology relative to the first iteration is  $< 1$  micron
- The RMS per-coordinate shift between first and second iterations of pseudo metrology is 0.36 microns
- So my methodology seems convergent/self-consistent

# Vector plots showing magnitude/ direction of corrections derived

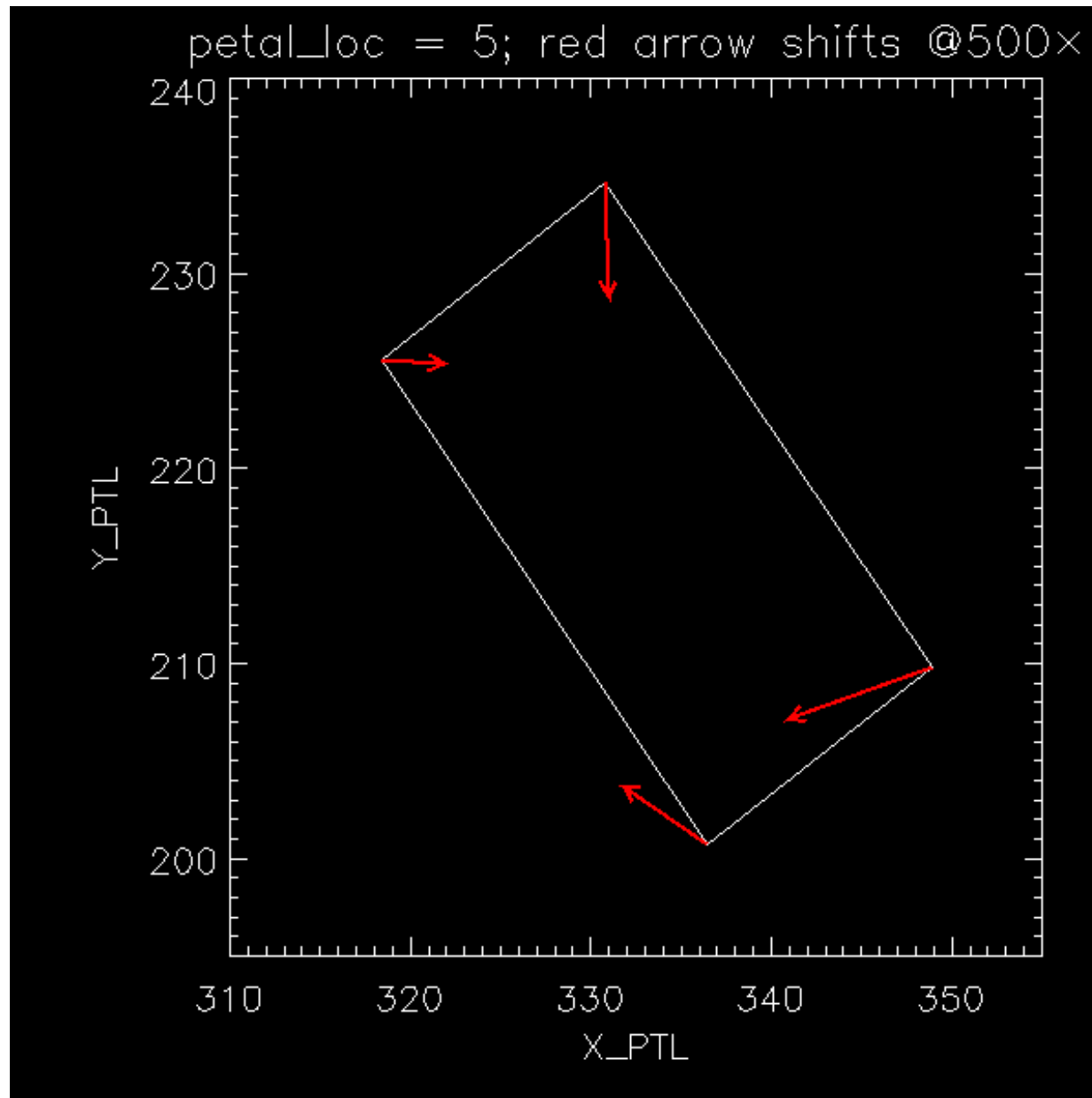


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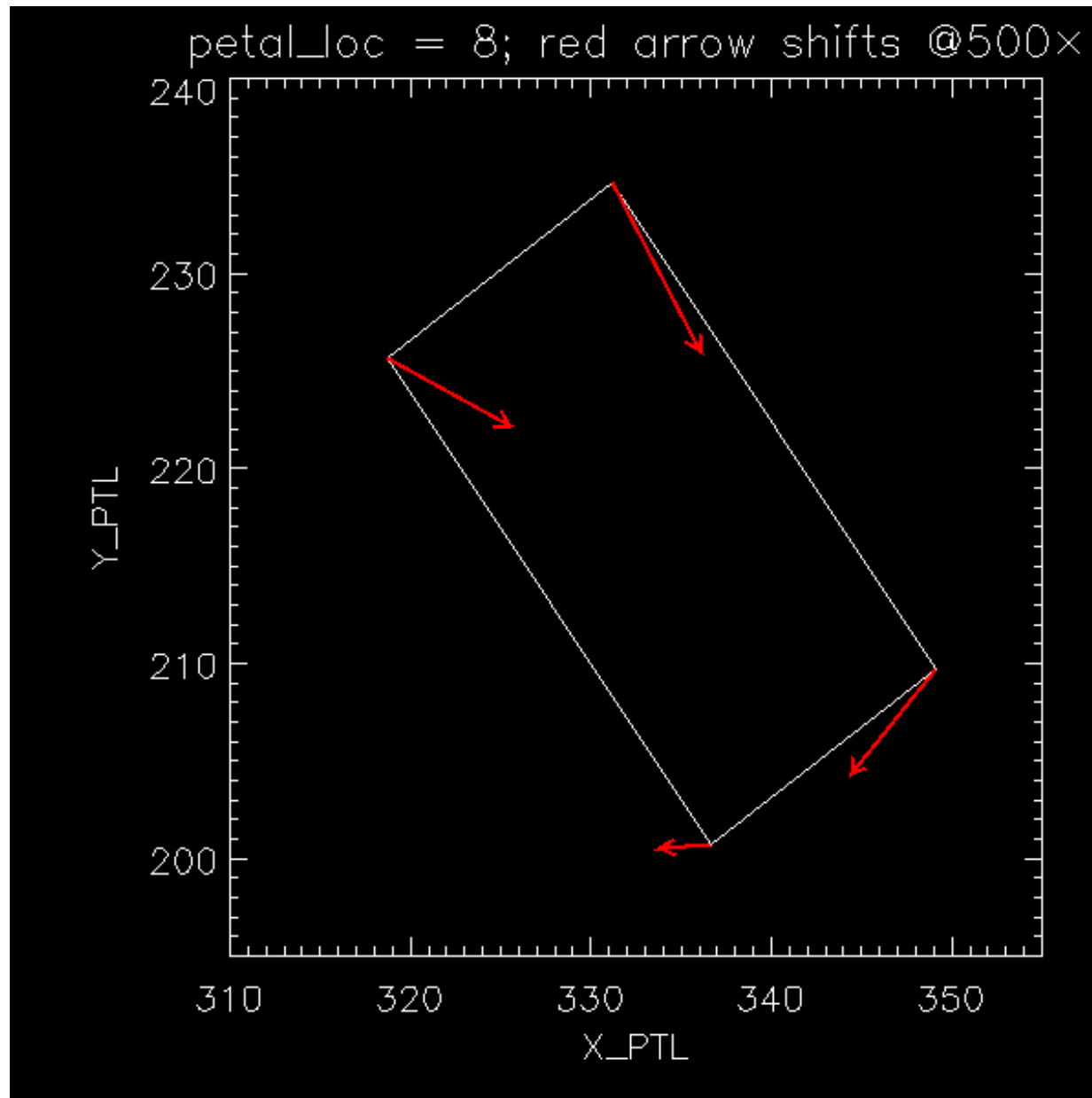




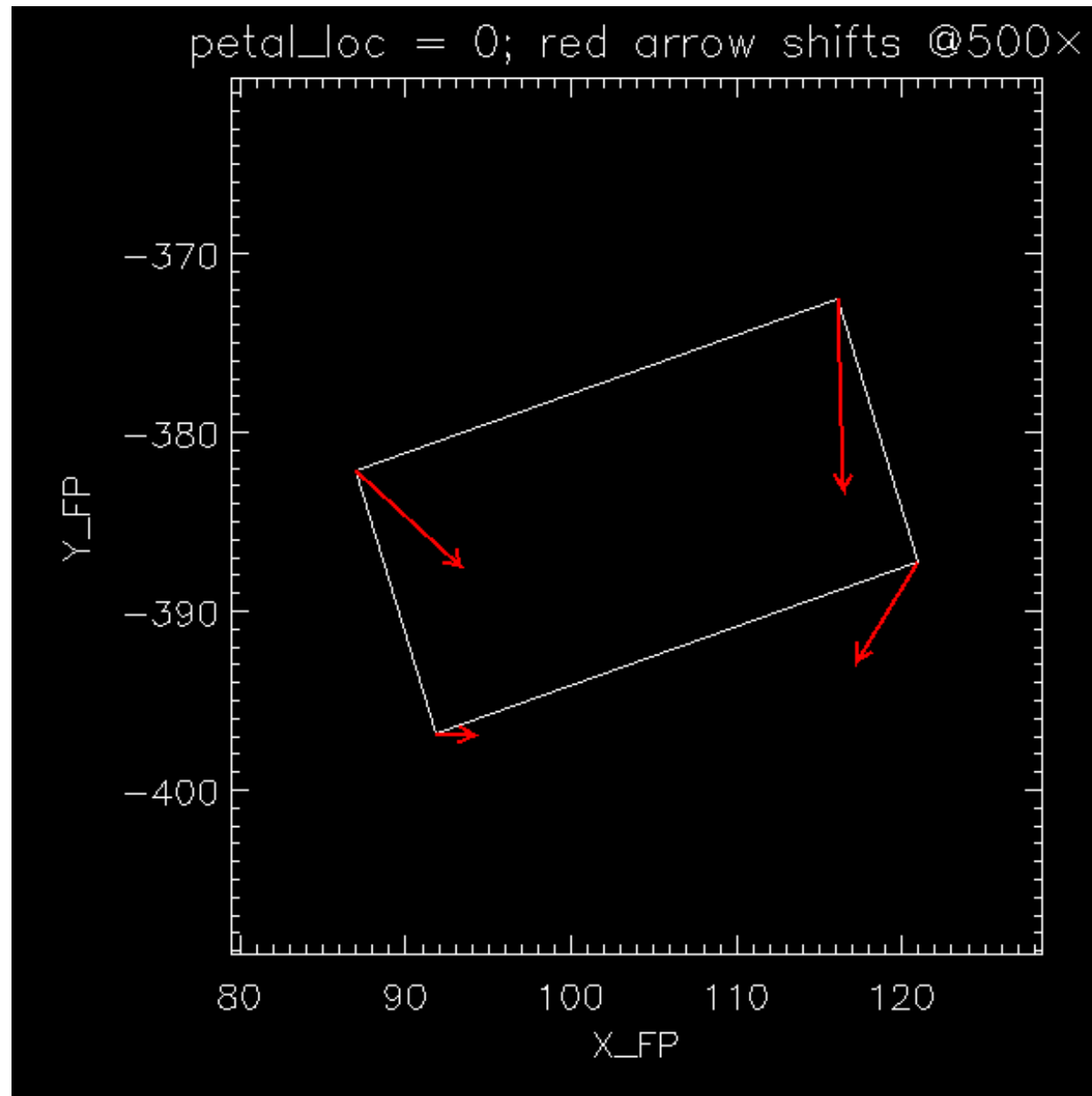
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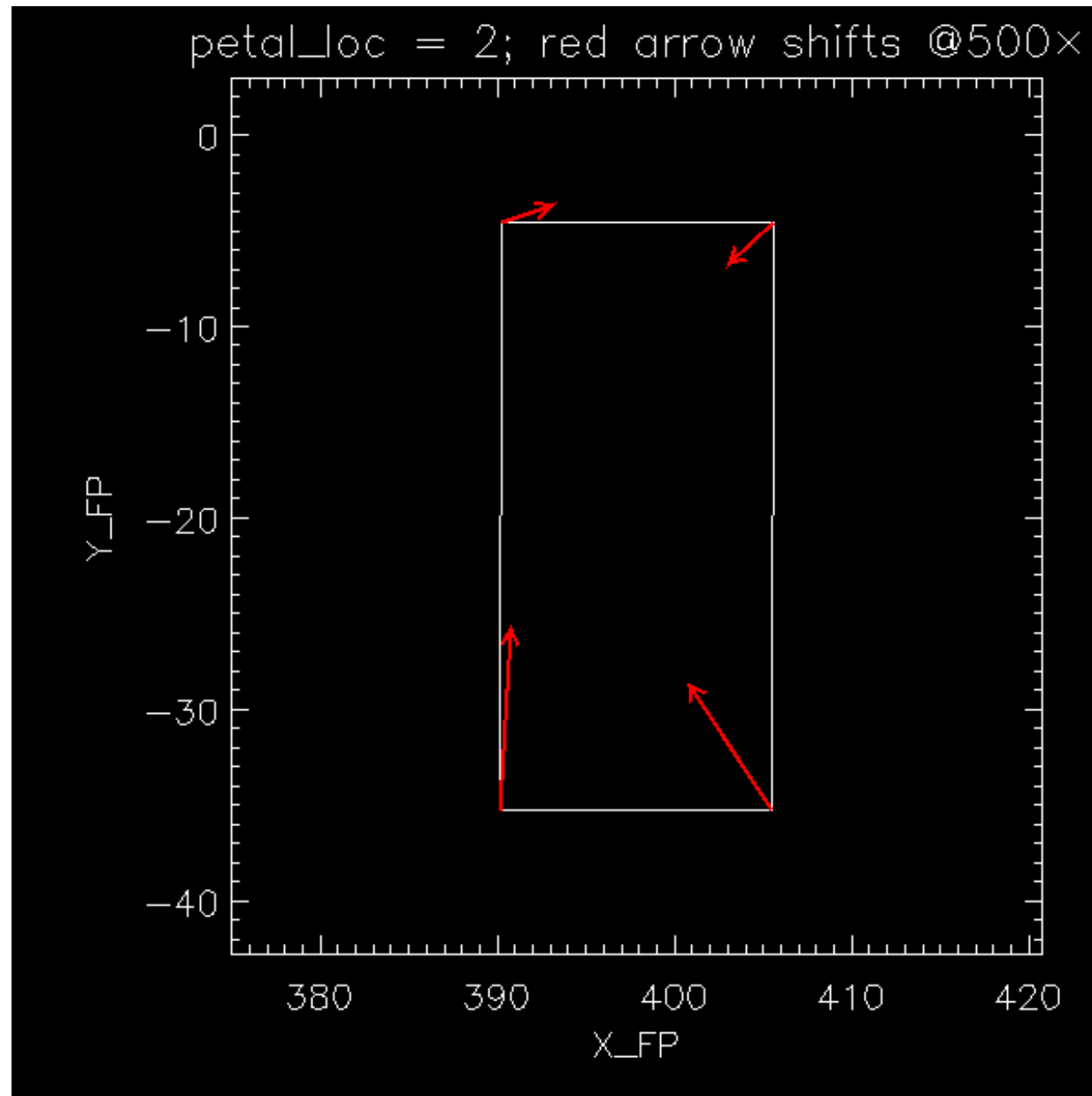
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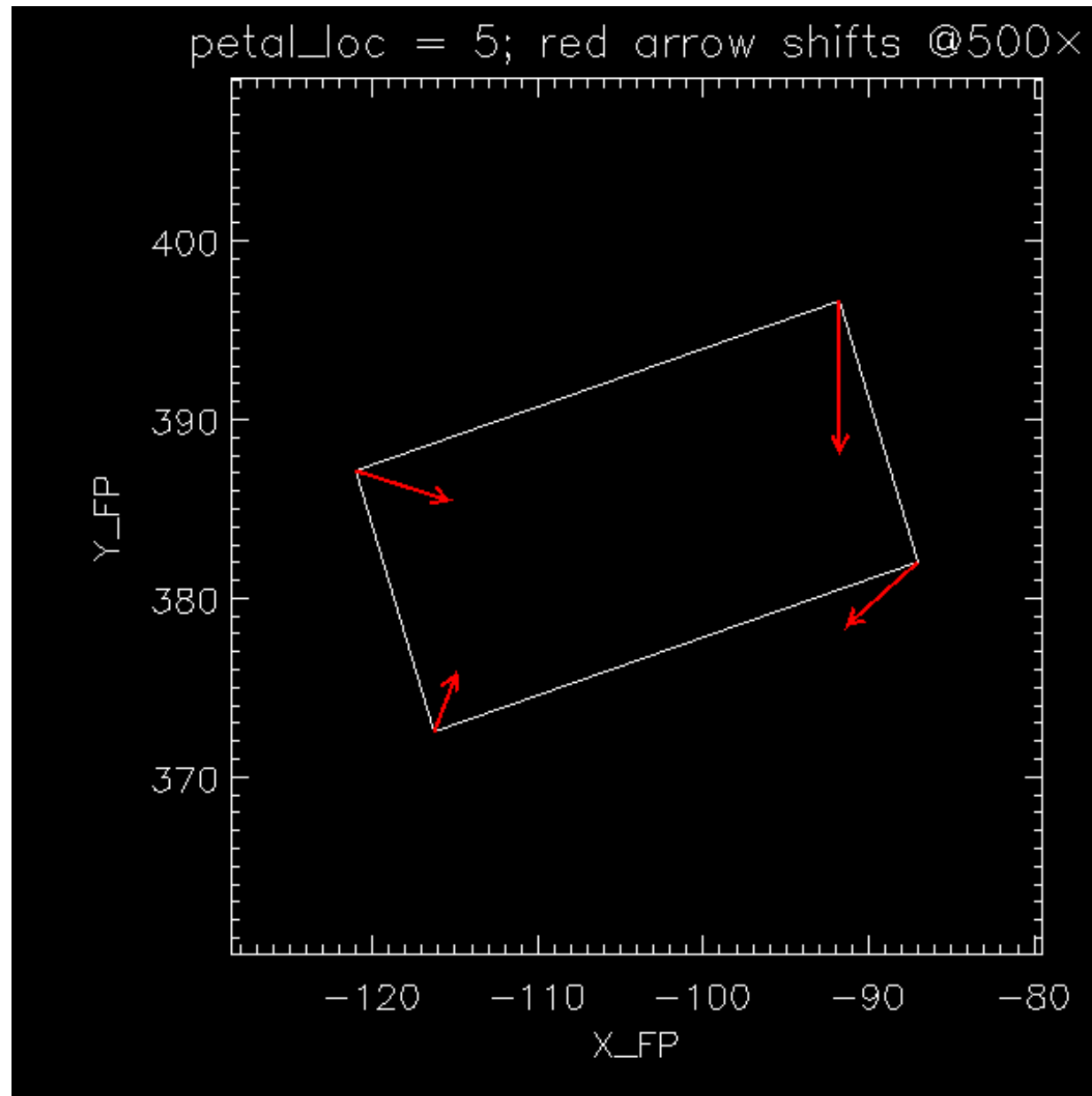
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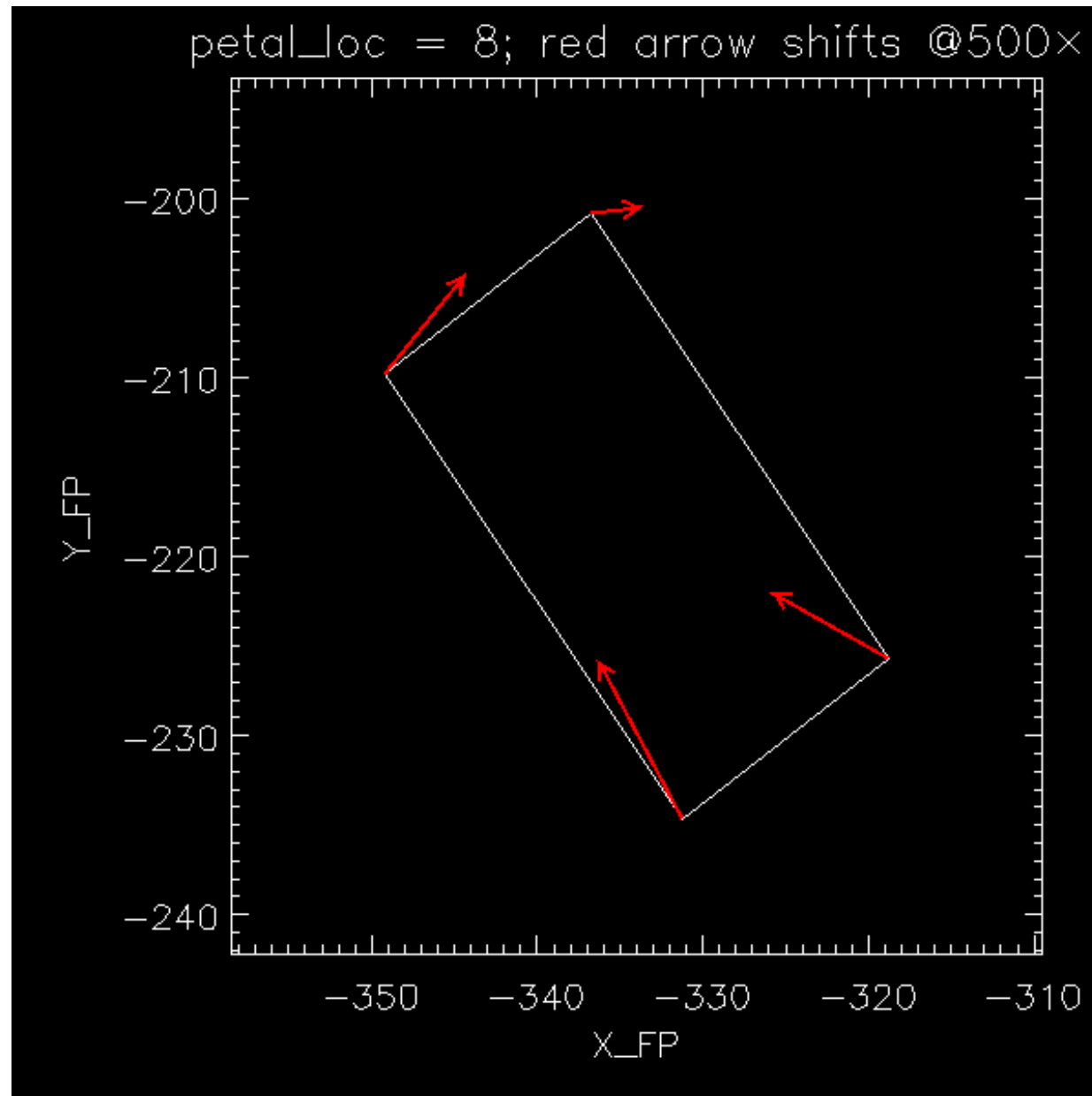
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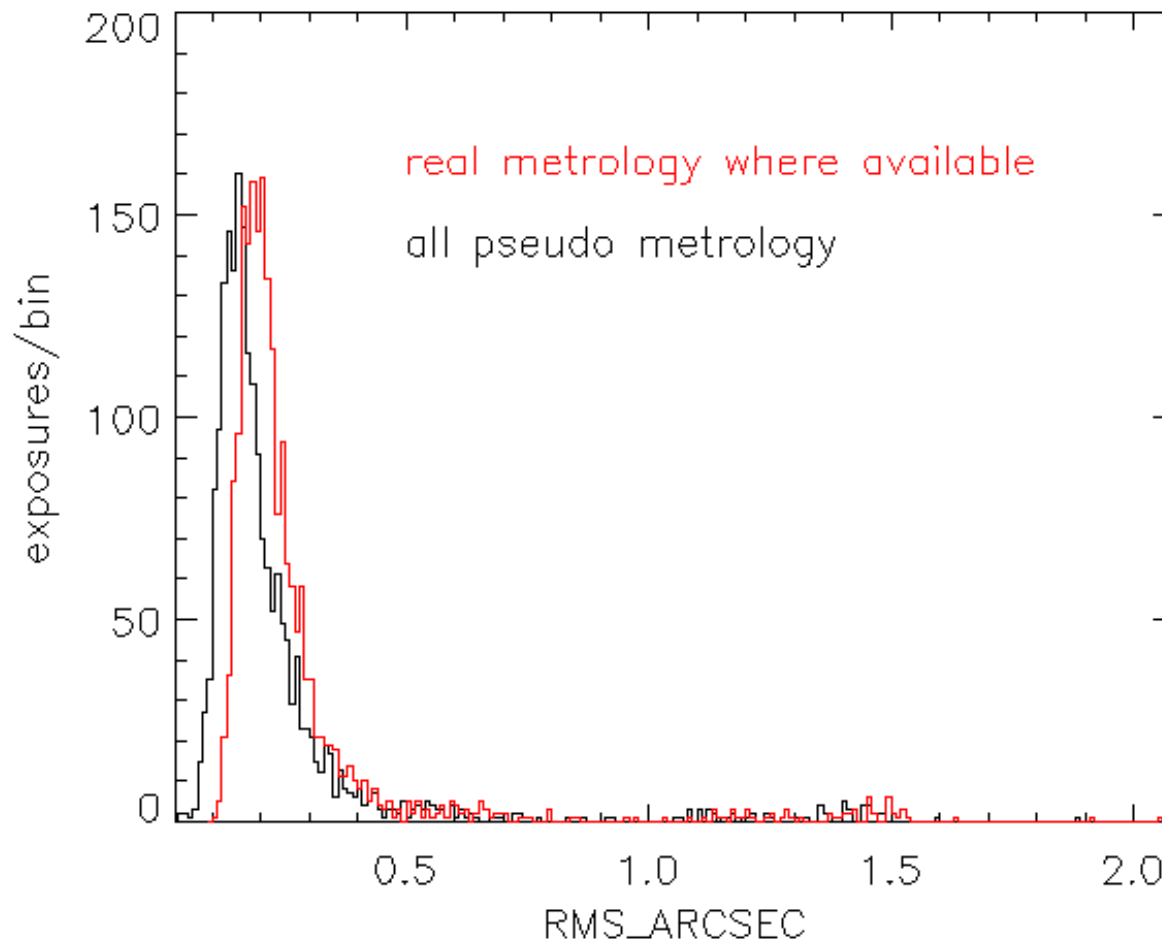
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# RMS\_ARCSEC with pseudo metrology replacing real metrology

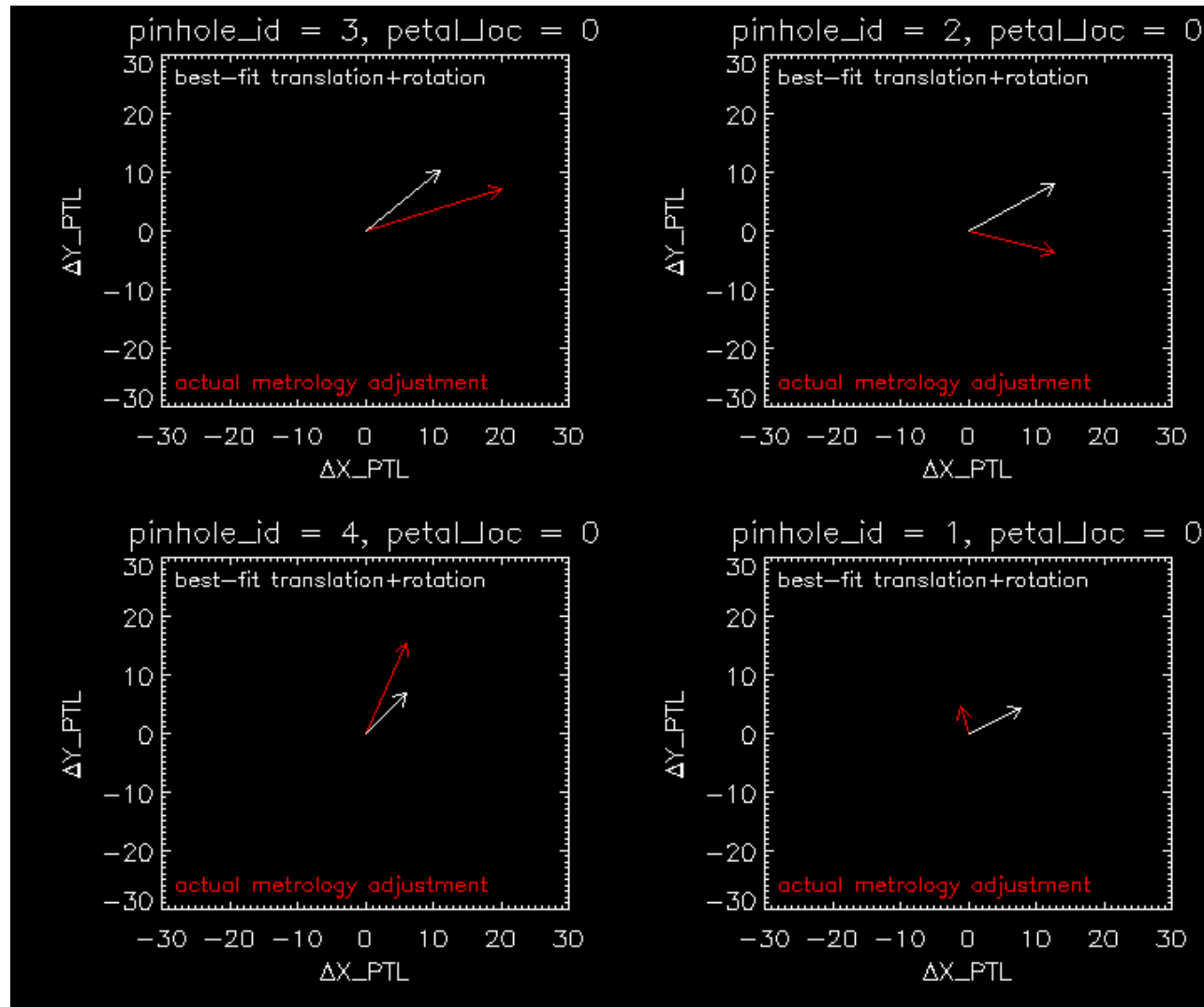
- Using real metrology when available:  
 $\text{median}(\text{RMS\_ARCSEC}) = 0.212$
- Replacing real metrology with tweaked metrology:  
 $\text{median}(\text{RMS\_ARCSEC}) = 0.172$
- So RMS\_ARCSEC is improved by ~20% when replacing the real metrology for GUIDE0, GUIDE2, GUIDE5, GUIDE8 with the tweaked metrology based on Gaia

# RMS\_ARCSEC with pseudo metrology replacing real metrology



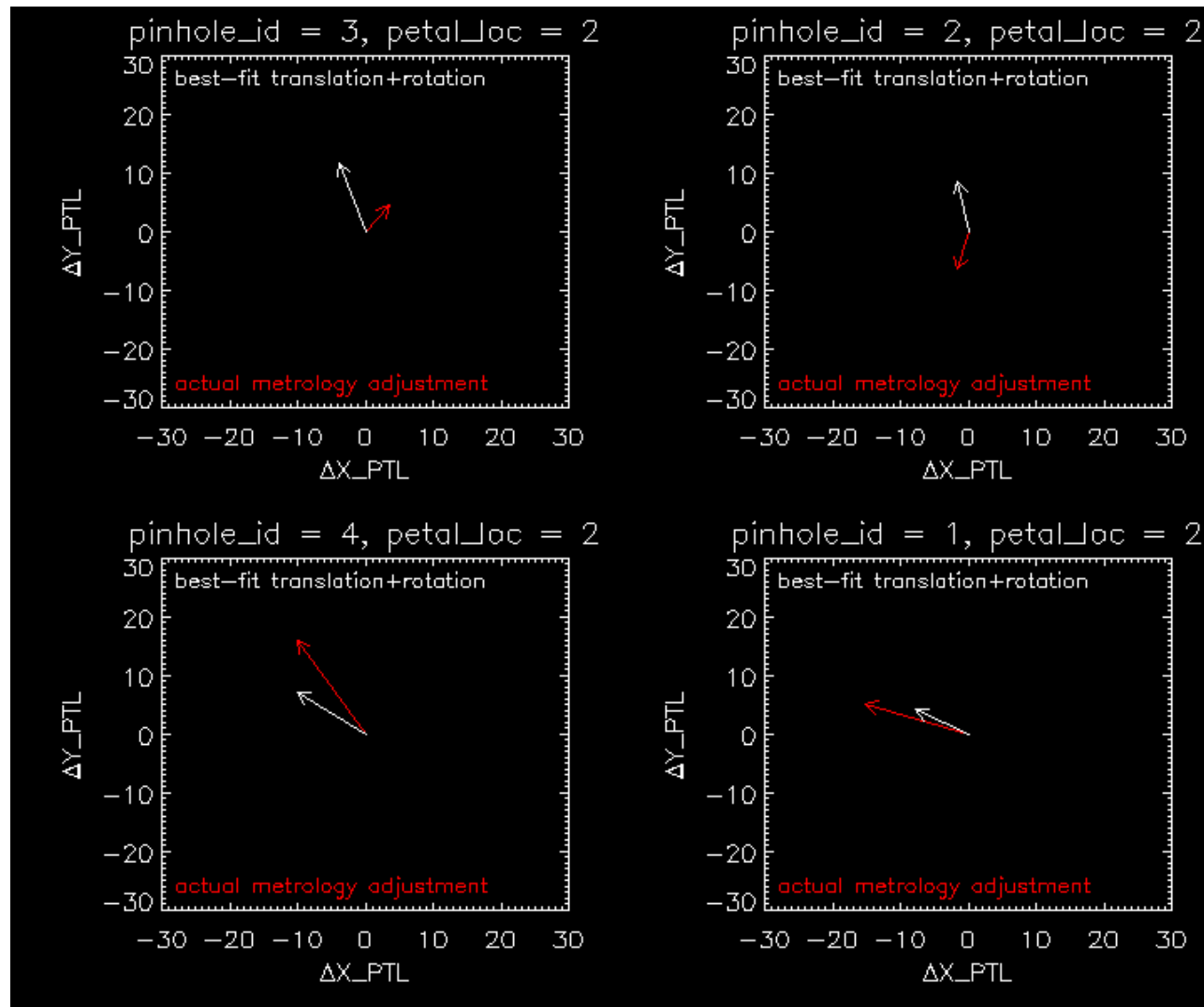


# Decomposing the metrology adjustments into rotation+translation



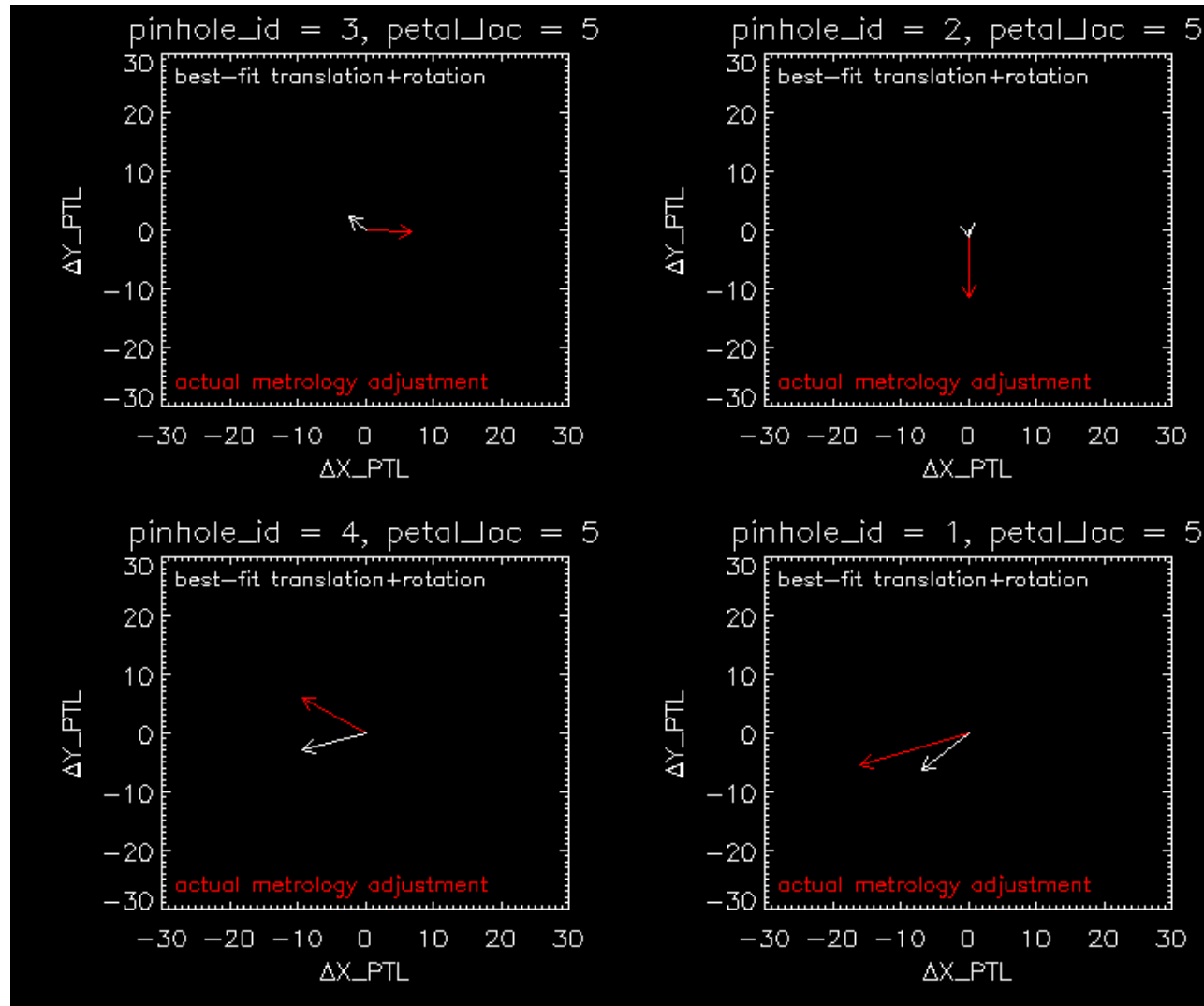
- The metrology tweaks don't decompose well into rotation (about the GFA center) plus translation; this seems consistent with my visual impression of the measured amplitudes/directions

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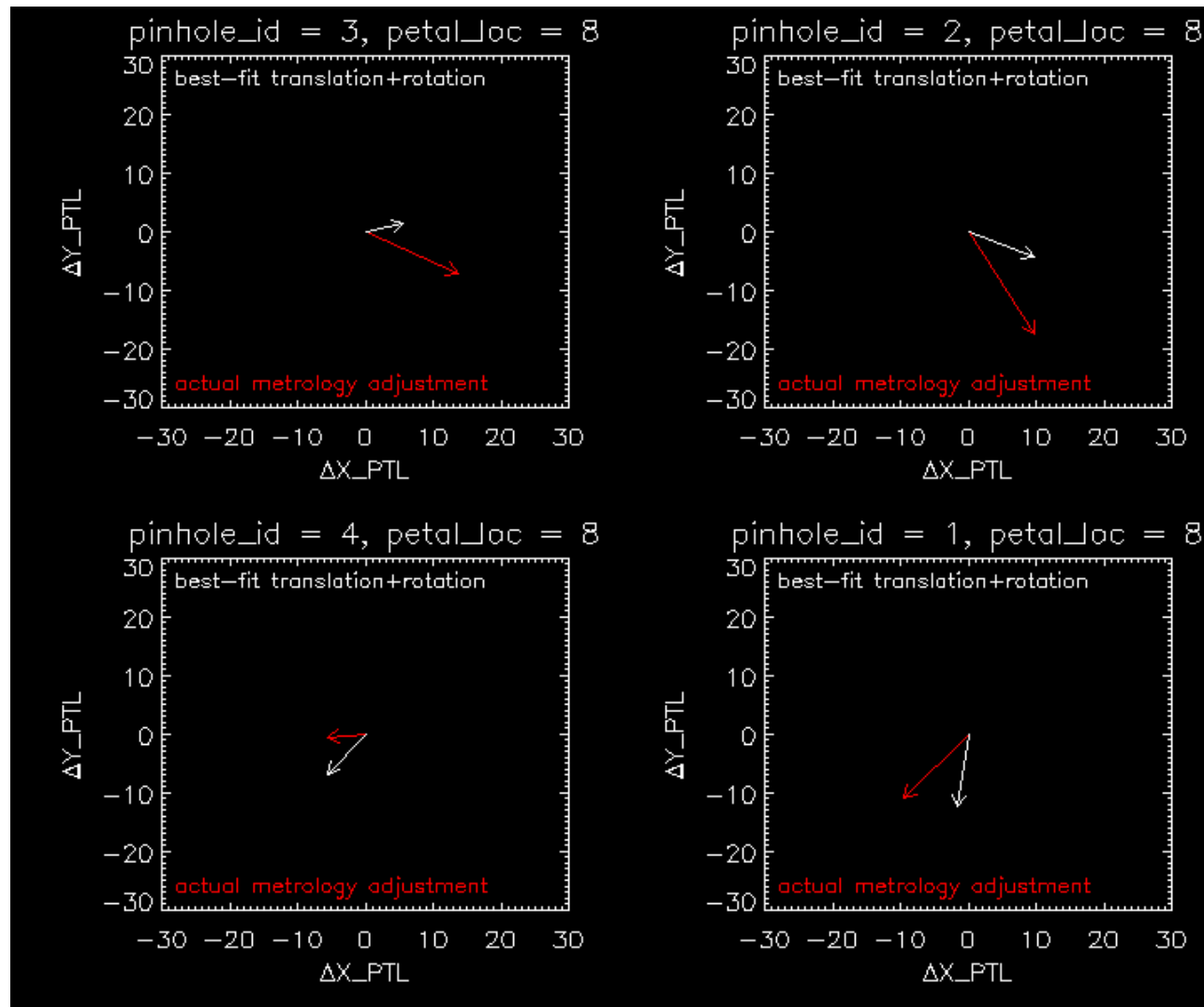
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